

Search Notes

Application/Control No.

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Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	171	3/30/2006	HHT

INTERFERENCE SEARCHED

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Interference search history printout		3/30/2006	HHT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM- TDB)_see search history printout	12/1/2005	HHT
EAST texh search updated (US- PGPUB; USPAT; EPO; JPO; DERWENT; IBM-TDB_see search history printout	3/30/2006	HHT